

# Search Notes



Application/Control No.

10/716,845

Examiner

DANH C. LE

Applicant(s)/Patent under Reexamination

WEAVER ET AL.

Art Unit

2683

## SEARCHED

Class	Subclass	Date	Examiner
455	520	12/10/05	DCL
	518		
	519		
	456.2		
	456.3		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Interference Search		12/10/05	DCL

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Inventor Name Search (Check for double patent)	12/20/05	DCL
EAST Search updated (USP, USPOB, EPO, JPO DERWENT)		
Lee Nguyen (455)		
Vuong Hien (455)		